

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/781,766	<b>Applicant(s)/Patent under Reexamination</b> HON ET AL.
<b>Examiner</b> Cuong Q. Nguyen	<b>Art Unit</b> 2811	

*See* INTERFERENCE SEARCHED *note.*

Class	Subclass	Date	Examiner